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(12) **United States Design Patent** (10) **Patent No.:** **US D977,504 S**
Ummethala et al. (45) **Date of Patent:** **** Feb. 7, 2023**

(54) **PORTION OF A DISPLAY PANEL WITH A GRAPHICAL USER INTERFACE**

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(**) Term: **15 Years**

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(51) **LOC (14) Cl.** **14-04**

(52) **U.S. Cl.**
USPC **D14/486**

(58) **Field of Classification Search**
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CPC H01L 22/20; H01L 22/12; G06F 3/048; G06F 3/0481; G06F 3/04817; G06F 3/0482; G06F 3/0483; G06F 3/04842; G06F 3/0485; G06F 3/04855; G06F 3/0486; G06F

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(57) **CLAIM**

The ornamental design for a portion of a display panel with a graphical user interface, as shown and described.

DESCRIPTION

FIG. 1 is a front view of a portion of a display panel with a graphical user interface showing our new design in a first image.

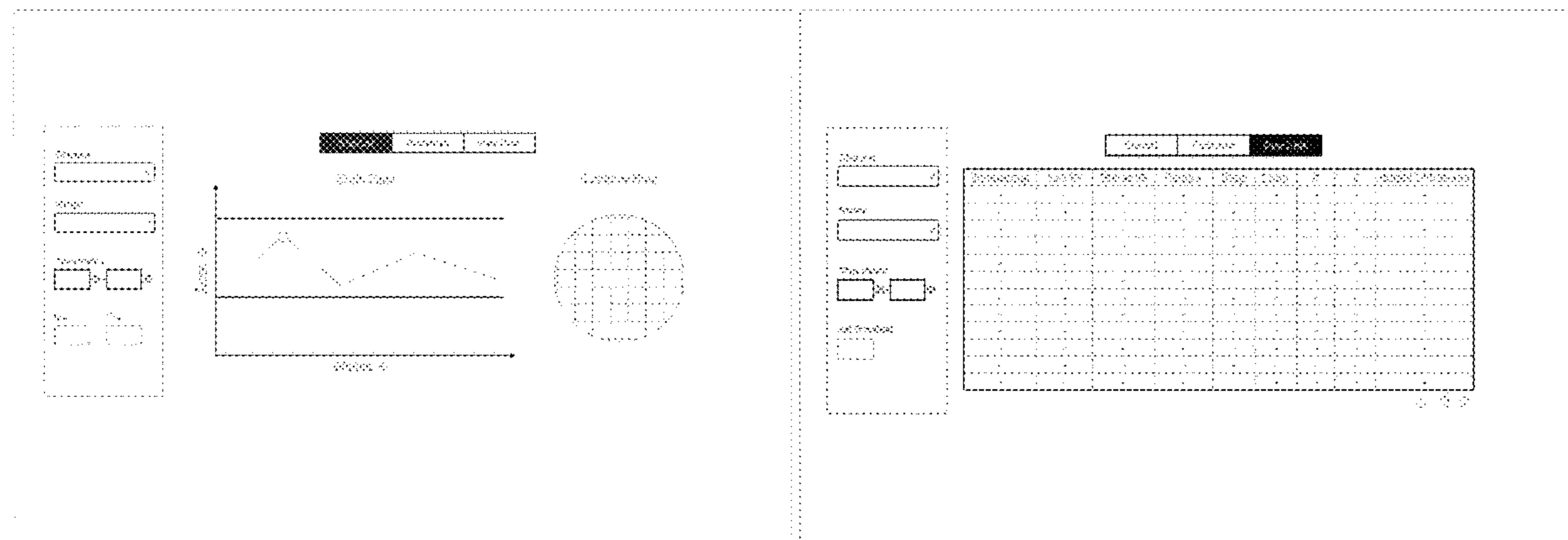
FIG. 2 is a front view of a portion of a display panel with a graphical user interface showing our new design in a second image; and,

FIG. 3 is a front view of a portion of a display panel with a graphical user interface showing our new design in a third image.

The broken lines including the showing of a portion of a display panel with the illustrated graphical user interface and the portions of the graphical user interface are included for the purpose of illustrating environmental structure and form no part of the claimed design.

The appearance of the transitional image sequentially transitions between the images shown in FIGS. 1-3. No ornamental aspects are associated with the process or period in which one image transitions to another image.

1 Claim, 3 Drawing Sheets



(58) **Field of Classification Search**

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See application file for complete search history.

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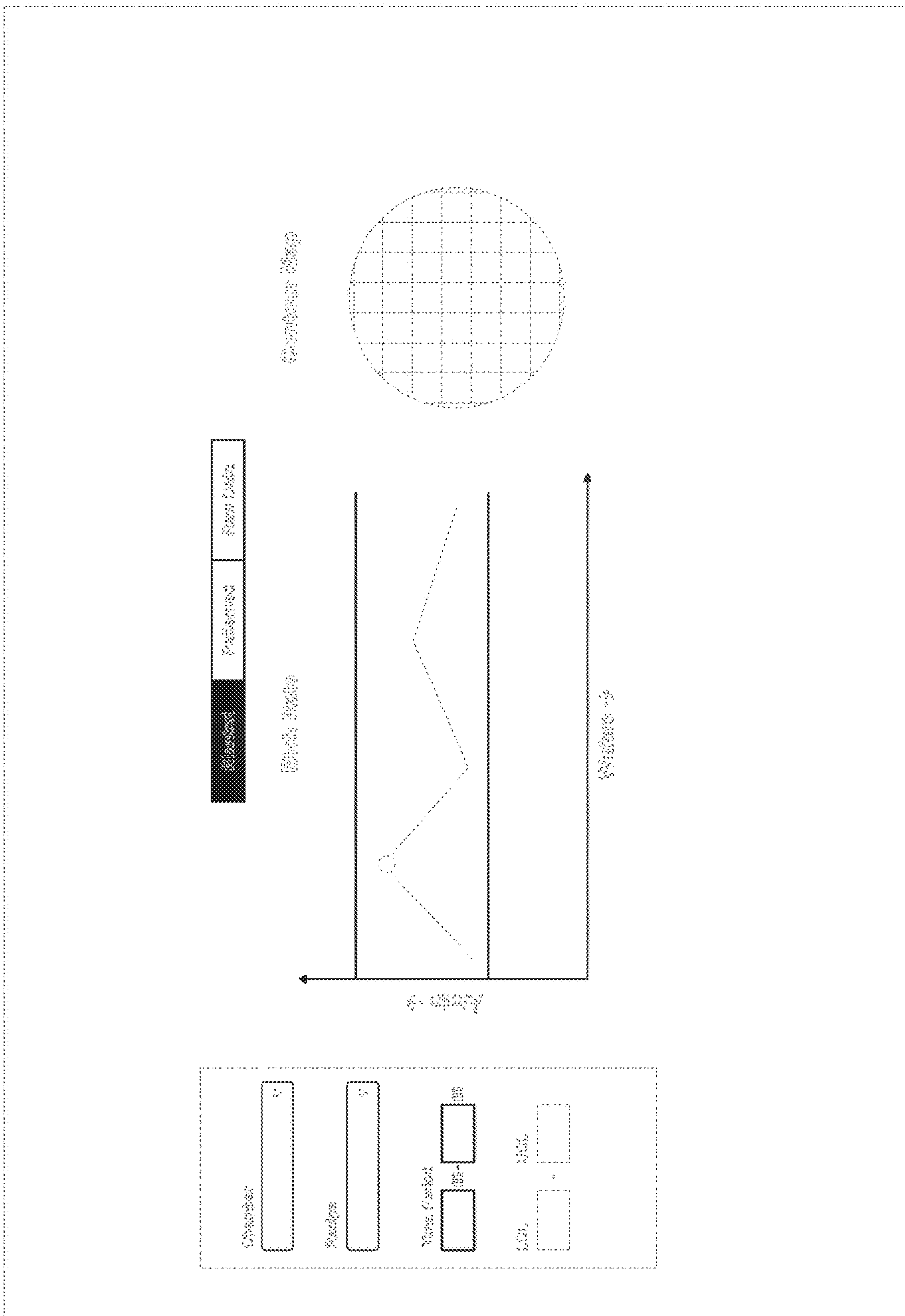


FIG. 1

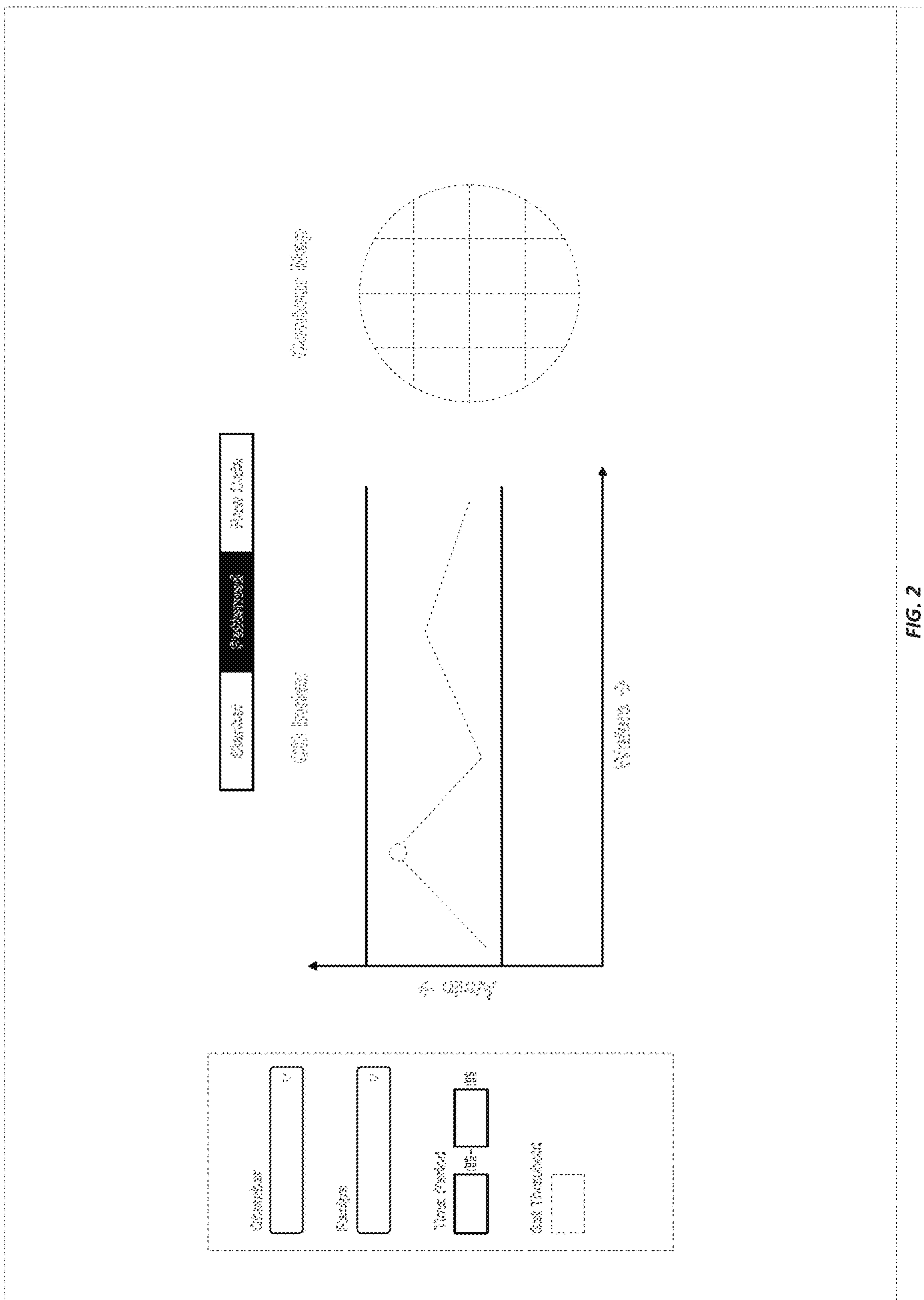


FIG. 2

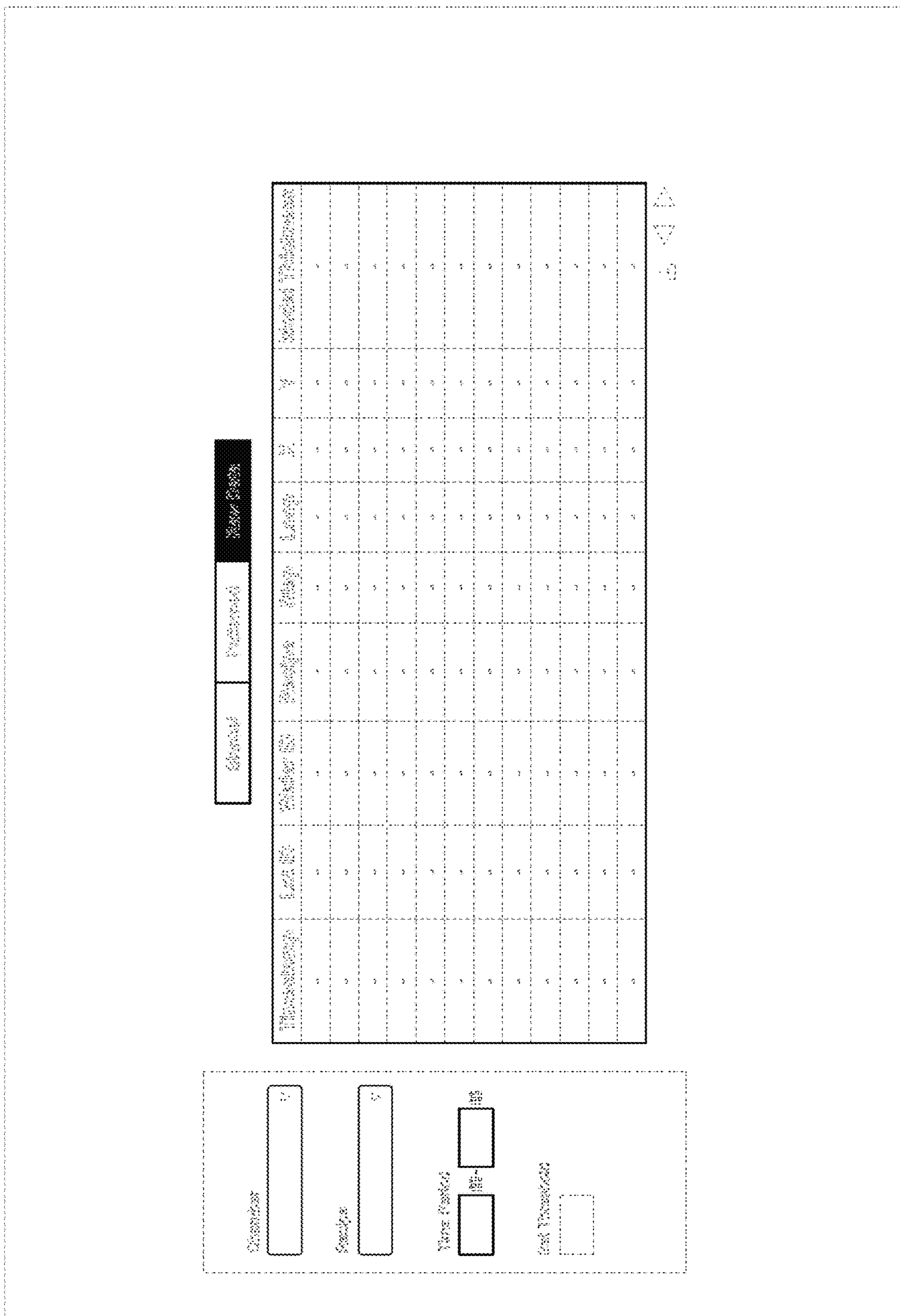


FIG. 3